Asylum Research AFMs are being used by leading researchers around the globe for characterizing nanoelectrical properties. A variety of their publications can be found at:

www.oxford-instruments.com/nanoelectrical-afm.

Figure caption: Kelvin Probe Force Microscopy surface potential overlaid on topography for flakes of boron nitride (small triangles) and graphene (large irregular features) grown on a copper foil substrate.

About Oxford Instruments Asylum Research

Oxford Instruments Asylum Research is the technology leader in atomic force microscopy for both materials and bioscience research. Asylum Research AFMs are widely used by both academic and industrial researchers for characterizing samples from diverse fields spanning material science, polymers, thin films, energy research, and biophysics. In addition to routine imaging of sample topography and roughness, Asylum Research AFMs also offer unmatched resolution and quantitative measurement capability for nanoelectrical, nanomechanical and electromechanical characterization. Recent advances have made these measurements far simpler and more automated for increased consistency and productivity. Its Cypher™ and MFP-3D™ AFM product lines span a wide range of performance and budgets. Asylum Research also offers its exclusive SurfRider™ AFM probes among a comprehensive selection of AFM probes, accessories, and consumables. Sales, applications and service offices are located in the United States, Germany, United Kingdom, Japan, France, India, China and Taiwan, with distributor offices in other global regions.

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